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APPLICATION NO.	FILING DATE	FIRST NAMED INVENTOR	ATTORNEY DOCKET NO.	CONFIRMATION NO.
10/772,375	02/06/2004	Satoshi Taniguchi	248178US-6 DIV	6784
22850	7590 05/02/2006		EXAMINER	
	OBLON, SPIVAK, MCCLELLAND, MAIER & NEUSTADT, P.C.  1940 DUKE STREET ALEXANDRIA, VA 22314  ART UNIT P. 2813		TUAN H	
			ART UNIT	PAPER NUMBER
			2813	
			DATE MAILED: 05/02/2000	6

Please find below and/or attached an Office communication concerning this application or proceeding.

		Application No.	Applicant(s)		
Office Action Summary		10/772,375	TANIGUCHI ET AL.		
		Examiner	Art Unit		
		Tuan H. Nguyen	2813		
Period fo	The MAILING DATE of this communication ap or Reply	pears on the cover sheet w	rith the correspondence address		
WHIC - Exte after - If NC - Failu Any	ORTENED STATUTORY PERIOD FOR REPL CHEVER IS LONGER, FROM THE MAILING D nsions of time may be available under the provisions of 37 CFR 1. SIX (6) MONTHS from the mailing date of this communication. O period for reply is specified above, the maximum statutory period are to reply within the set or extended period for reply will, by statute reply received by the Office later than three months after the mailine ed patent term adjustment. See 37 CFR 1.704(b).	DATE OF THIS COMMUNI 136(a). In no event, however, may a will apply and will expire SIX (6) MOI e, cause the application to become A	ICATION. reply be timely filed  NTHS from the mailing date of this communication. BANDONED (35 U.S.C. § 133).		
Status					
1)	Responsive to communication(s) filed on 15 A	April 2005.			
		s action is non-final.			
3)	Since this application is in condition for allowance except for formal matters, prosecution as to the merits in				
	closed in accordance with the practice under	Ex parte Quayle, 1935 C.[	D. 11, 453 O.G. 213.		
Dispositi	ion of Claims				
5)□ 6)⊠ 7)□	Claim(s) <u>1-9</u> is/are pending in the application.  4a) Of the above claim(s) is/are withdra  Claim(s) is/are allowed.  Claim(s) <u>1-9</u> is/are rejected.  Claim(s) is/are objected to.  Claim(s) are subject to restriction and/or				
Applicati	ion Papers				
	. The specification is objected to by the Examine	er			
	The drawing(s) filed on is/are: a) acc		by the Examiner.		
	Applicant may not request that any objection to the				
11)	Replacement drawing sheet(s) including the correct The oath or declaration is objected to by the Ex				
Priority (	ınder 35 U.S.C. § 119				
a)	Acknowledgment is made of a claim for foreign All b) Some * c) None of:  1. Certified copies of the priority document 2. Certified copies of the priority document 3. Copies of the certified copies of the priority application from the International Burea See the attached detailed Office action for a list	ts have been received.  ts have been received in A  ority documents have beer  u (PCT Rule 17.2(a)).	Application No. <u>10/287,682</u> . In received in this National Stage		
Attachmen	t(s)				
Notic	e of References Cited (PTO-892)		Summary (PTO-413)		
3) 🔲 Inforr	e of Draftsperson's Patent Drawing Review (PTO-948) mation Disclosure Statement(s) (PTO-1449 or PTO/SB/08) r No(s)/Mail Date		(s)/Mail Date Informal Patent Application (PTO-152)		

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## **DETAILED ACTION**

## Claim Rejections - 35 USC § 103

The following is a quotation of 35 U.S.C. 103(a) which forms the basis for all obviousness rejections set forth in this Office action:

(a) A patent may not be obtained though the invention is not identically disclosed or described as set forth in section 102 of this title, if the differences between the subject matter sought to be patented and the prior art are such that the subject matter as a whole would have been obvious at the time the invention was made to a person having ordinary skill in the art to which said subject matter pertains. Patentability shall not be negatived by the manner in which the invention was made.

Claims 1-9 are rejected under 35 U.S.C. 103(a) as being unpatentable over Background of the invention in view of Mishra et al. (US Pat. No. 5.053,348).

Background of the invention, figs. 10-11 and related text in the present specification discloses substantially the claimed method for forming a field effect semiconductor device including the step of forming a T-shaped gate electrode 6 on a gallium nitride-based compound semiconductor; forming a source electrode 8 and a drain electrode 9 lower than the bottom face of an overhang of the T-shaped gate electrode (fig. 11C). Background of the invention fails to teach the use of gate electrode as a mask for forming self-aligned source/drain electrode.

Mishra et al., in a related method for fabricating of self-aligned T-gate HEMT as shown in figs. 1-20 and related text on col. 3-7, discloses the use of gate electrode 34b as a mask in forming self-aligned source/drain electrode 48, 50 (fig. 13 and text on col. 6, first two paragraphs).

It would have been obvious to one having ordinary skill in the art at the time the invention was made to have used gate electrode as a mask as suggested by Mishra et al. in forming self-aligned source/drain electrode in the conventional process for forming

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a field effect semiconductor device as disclosed in the Background of the invention since it would provide a small source-gate and drain-gate spacings which would improve the device speed, operation at extremely high frequencies.

With respect to the gate electrode material, and thickness, since the high melting point metal is a well-known material for use in forming gate electrode, it would have been obvious to those skilled in the art to select a suitable material and thickness for gate electrode in forming high speed device.

The prior art made of record and not relied upon is considered pertinent to applicant's disclosure. Pan et al., and Endoh disclose the use of gate electrode as a mask for forming self-aligned source /drain electrodes; and Furukawa et al., Kubena, and Caviglia teach the use of high melting point metal for forming gate electrode.

Any inquiry concerning this communication or earlier communications from the examiner should be directed to Tuan H. Nguyen whose telephone number is 571-272-1694. The examiner can normally be reached on 9AM-5:30PM.

If attempts to reach the examiner by telephone are unsuccessful, the examiner's supervisor, Carl Whitehead Jr. can be reached on 571-272-1702. The fax phone number for the organization where this application or proceeding is assigned is 571-273-8300.

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Information regarding the status of an application may be obtained from the Patent Application Information Retrieval (PAIR) system. Status information for published applications may be obtained from either Private PAIR or Public PAIR. Status information for unpublished applications is available through Private PAIR only. For more information about the PAIR system, see http://pair-direct.uspto.gov. Should you have questions on access to the Private PAIR system, contact the Electronic Business Center (EBC) at 866-217-9197 (toll-free).

Tuan H. Nguyen
Primary Examiner
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